A Complete Bibliography of Publications in *Technometrics* for the decade 1970–1979

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0.5 [Lad77]. 18 [Joh73a]. 2 [BN72]. 2^m [SC71]. 2^n [Joh79]. 2^{n-k} [Joh79]. 2×2 [MDM77]. 3 [Lin79]. 3^n [Hok74]. ^{4} [Dic74]. ^{5} [Dic74]. ^{n} [TW70]. A [Bad70, Bor72]. α [AS73, McC78a]. $A \subset B$ [Bad70, Bor72]. B [Bad70, Bor72]. β [AS73, GPU76]. C_P [Mal73, Ano73i, Ken71]. D [GK77a, Luc78, Mit74a, Mit74b, MB78a, MB78b, NGM70, SD75]. F [DW72, DW73, HH77, J.79u, Joh73b, Obe77, Pap72, PW72, HB71]. k [HP73, Ode71, WK71, Zei73]. $\log Y$ [Scl72]. m [FM77, HP73]. $m \leq 6$ [SC71]. N [Shu71, Gre70b, Sap73]. $n = 92$ [Wat70a]. O [MHL74]. p [Dun78a, FM77, For72, Lad77, MC72]. $P(Y < X)$ [KKS76]. $P[Y < X]$ [WK77]. $\Pr(Y < X)$ [Dow73]. $\Pr\{Y < X\}$ [JTS75, Ton74, Ton75]. R^2 [DH74]. s [Bha73, Lik74]. s^n [AT79]. σ^2 [JMM78]. t [AS73, KP79, Ros75c, SI70, TC72, YM74]. T^2 [BJN71]. T_M^2 [JH79]. V [SC71]. W [GH79, HH73, HL76, Ste78, Tho75]. X [Scl72]. Y [Scl72]. $|X'X|$ [Ano71a, Ano72e, Ano73h, BD71, Dyk71, Eva79].

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2 [Che71, J.79f, Sne74]. **21** [Kit81]. **25** [K.73a].

3 [BCK78, J.76h].

4 [J.77k].

5 [J.78o].

77 [Hea78]. **'78** [J.79n]. **781** [BS79].

80f [Kit81].

A. [GW71, HH73]. **Abadie** [Sha71]. **Abridged** [Ano71f]. **Absolute** [JH79, NW79]. **Absorbing** [Bri74]. **abstract** [Tuk70]. **Abstracted** [J.75c]. **Abstracts** [Ano70a]. **Accelerated** [BS71, MH78, Nel72a, NK76, NM78, Sha78, Sin71, Sin73]. **acceptability** [McC78a]. **Acceptable** [OB76]. **Acceptance** [Bin74b, BLB73, MCM75]. **Accountability** [Lev79]. **Accounting** [PB77]. **Accuracy** [Gru73b]. **Adaptive** [HR75, MRR78, RRH73]. **Addendum** [Ano71a, Ano77a, CL71, D'A71a]. **Addition** [Bor72]. **Additive** [Man71a]. **Adequacy** [HJF78, McK79]. **Adequate** [SD77, Ell78]. **Adjacent** [AJ77]. **Adjusted** [MHL77b]. **Adjustment** [CH74]. **Advances** [Law75b, J.77a]. **Advisory** [K.74e]. **Affairs** [Bon77]. **after** [Kow70, Lem74]. **against** [EB75, Ode71]. **Age** [CH74, IS76, RR76, Sch71b]. **Agreement** [Leo70]. **Agterberg** [Jon76b]. **AIC** [Kit81, Kit79]. **Aid** [CO75, Sne75a]. **Aided** [Cha70a]. **Aims** [Bon76b]. **Air** [Ano73j, CG76, Mar73, MS73, Sin72]. **Aircraft** [Bur73, Pas79]. **Alan** [Fie73, Hei76]. **Albert** [Web73]. **Alder** [Woo74b]. **Alfred** [Rog70c]. **Algorithm** [BD72a, GH79, HG73, HL76, Jon76a, LF79, Mit74a, RJ78]. **Algorithmic** [J.79b]. **Algorithms** [Ens76, JS76, YC71, Gor76, J.79u]. **Allan** [Har75, Jac80]. **Allin** [Kup71]. **Allocation** [CHH$^+$71, Gro72, Har74, BN72]. **Allocations** [Spr79]. **Alternate** [GM79, ZNL79]. **Alternating** [HD70]. **Alternative** [BA70, HM77, Igl73, Man71d, Sac72]. **Alternatives**

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[AF76, Her70, Sar71]. **Boundary** [And75]. **Bounds** [Fin76, FW74, Gru71b, Gru71c, JL79, KARR75, Law75a, Man70a, MF73, MG74, MF75a, MF77, Ury72]. **Bowker** [Web73]. **Box** [Add79, And70, Hil74, Kle77, GK77a, J.79p]. **Boyce** [Gor76]. **Bradley** [Bel70]. **Bradu** [Ano78e]. **Branch** [AF76]. **Branch-and-Bound** [AF76]. **Brandt** [Dav77]. **Bremner** [Kal75]. **Breslow** [J.79h]. **Bressler** [Kno71]. **Brian** [J.79i, K.71a, Ket75]. **Bridge** [ZNL79]. **Brillinger** [Weg76]. **Brodeau** [J.78m]. **Bronchitis** [Ens78]. **Bross** [Bon77]. **Brown** [K.71a, Hea78, Joh75]. **Brownian** [CF76, Nád73, PK76, SS74, Ser73]. **Bruce** [Rog70b]. **Brumat** [J.78i]. **Brunk** [Hal77b, Kal75]. **Brunner** [Jac80]. **Bryant** [J.76e, Hay73, J.76d]. **Buddy** [Rus73]. **Building** [Goo71]. **Bulk** [BR75]. **Burdick** [J.78j]. **Burman** [Wat70a]. **Burr** [Aus73]. **Business** [Ham75, J.78p, Joh75, Jon73, Kin79b, Hun70].

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[CR79, Dun71, Ens76, HW75, Kus79, Low76, MA78]. **Classifications** [Goo71, HG73]. **Classified** [Dra79]. **Claudia** [Gro77]. **Clelland** [Joh75]. **Clinical** [FH79, LSYF79]. **Close** [MC72]. **Closed** [BM74, BM76, Ell76, PW77]. **Closed-Loop** [BM74, BM76, Ell76, PW77]. **Cloud** [DV78]. **Cloud-Seeding** [DV78]. **Cluster** [Ens76, Ket75]. **Clustering** [JK74]. **Clusters** [CBI79, YB76]. **Cochran** [J.78n, LH74]. **Code** [MBC79]. **Codes** [ZNL79]. **Coefficient** [Ano75e, Fil75, IM70, Kow71, Zei73, McC78a]. **Coefficients** [AR73, For72, JH73a, Wol77a]. **Coherence** [CP75]. **Collected** [K.73b]. **Collection** [J.76f]. **Combination** [Pap72]. **Combinations** [Coh72, Joh71a]. **Combining** [EP71, Lev70]. **Comment** [BC71, Cro71]. **Commentaries** [CGO07]. **Comments** [Cor75, HK77, Mal73, DV79, MK70]. **Commission** [Car77b]. **Comparative** [BJN71, Bon76a]. **Comparing** [AB71, Ber78, Jae70, MDM77, Nel72a, Rub76, Sal75b, SS76, BN72]. **Comparison** [BM78, CM71, DW73, Dub73, Fed75, FH79, GK77a, GK77b, GH70, Gri70, Gru73b, GWM76, HN70, HW75, Hin77a, Kam73, Kam77, KP71, LSYF79, Low70, Luc76, MBC79, MH78, MPB70, MA78, San73, TA75, Ury76, Vin76, WC78, HK77]. **Comparisons** [IM70, SdV73, SU79, Ury76, BN72]. **Compartmental** [Gri79]. **Competing** [Moe74]. **Competitive** [Nay72]. **Complete** [Ano73k, Bis78, Coh65, Coh72, EB73, EB79, MF77, MHL74, SW72]. **Complex** [Bri74, Hun74, Sne76, Cas76]. **Component** [EP71, GC79, GH79, Gru71b, HL76, JM79, JS76, Krz79, Low76, MG74, Sar71, Var70, Bha73]. **Components** [CS76, DS77a, GG70b, JH73a, JH79, MA78, Par78b, See70, SS78, TA71, Wol78, YC78]. **Composite** [HP78, Luc74]. **Composited** [Ede74]. **Compound** [BK70a, Cho79, Fal70, Boa73]. **Compressed** [Kam74]. **Comprised** [WK71]. **Computation** [CGO07, Fur71, Sch76, Som70, Yue78, K.71e]. **Computational** [Dav77, LH70]. **Computations** [J.77b, McC75a]. **Computer** [BH70, BCK61, Cha70a, Eva79, Gri72, Gro77, Hea78, Hub78, JB76, MBC79, Mil72b, Mit74b, Sie75, Wig76, BCK78, Mer72, Nay72]. **Computer-Aided** [Cha70a]. **Computers** [Cha70a, J.79q, Mul70]. **Computing** [HH73, KKM79, Mar76]. **Concentric** [CK79]. **Concept** [NGM70, Buc73]. **Concepts** [Bis72a, Car74, Sim76, SM76, Har77, Mih77, Mih75, Woo74a]. **concerning** [AK71, Law71]. **Condition** [Law77b, MH77]. **Conditional** [Ham72b, Jae74, Kap75, Sor71]. **Conditions** [Krz77, See73]. **Conference** [K.74e]. **Confidence** [AJ77, BS79, BWL78, Cha79, CM71, DV78, Dun78b, Eas78, EB78c, Fin76, FB75, Gaf78, Her70, Jae70, Jon71, Kam72, Kam73, Kam74, Kap75, Kus79, Lan72, Law78, LR78, Man70a, MF73, MG74, MF75a, MF77, MN77, Obe77, Pat76a, Ros75c, Sar71, Sch74a, SW75, Tar76, TBA70, TC75a, TC73, TS79, Ury72, TC72]. **Conflicting** [J.78b]. **Conjecture** [AK71]. **Conover** [Bha72]. **Consideration** [PDB77]. **Considerations** [GM79]. **Consistent** [IS76]. **Constant** [CK79, FR72]. **Constants** [Aus73]. **Constrained** [Ano76e, HB78, Sne75b, TW70]. **Constraints** [HS73].

Constructed [Dun78b]. **Constructing** [BCK61, BCK78]. **Construction** [CM71, EB78a, Law75a, Mit74a, Mit74b]. **Consultants** [Wat70b]. **contain** [HP73]. **content** [GPU76]. **Contigency** [MDM77]. **Contingency** [Gar71, Goo71, JK71, Odo78]. **Continuity** [Ham74]. **Continuous** [Che71, Fre74a, Hol75, RR76, Sac72, Sha79]. **Continuously** [Kao72]. **Contour** [GW71]. **Contrasts** [Par78b, Ury76]. **Contributions** [Ing78b, J.76a, J.78c]. **Control** [AB79, Ano77h, Aus73, BR79, BH78, Bin74b, Chi75, Dun78a, Dun77b, GW71, Gru73a, JM79, K.74a, Kab74, Luc73, Mac76, Pat73, RSO72, Rey75, ST73, SdV73, TW72a, BN72, Bis72b, J.79d, Kle77, Tsi78, Woo75, Ziz78]. **Convergence** [Ber72b, Sne70]. **Convolutions** [Bai74a]. **Cooley** [O'F73]. **Coordinate** [Kow70, Nád70a]. **Cornell** [Kup71]. **Correct** [Dun71]. **Correcting** [BH74]. **Correction** [AR79, Ham74, MM73]. **Correlated** [Shu71]. **Correlation** [Ano75e, AR73, BJ75, Fil75, Haw75, JB74, Kow71, Par70, Wol77a]. **Corrigenda** [Ano73f, Ano79e, Ano79f, Ano80a, Ano80b, Kit81, Mih77]. **Corrigendum** [Ano72g, Ano72e, Ano72f, Ano73g, Ano73h, Ano74f, Ano75e, Ano77a, Ano79g, Ano80c, Ano84]. **Cosines** [Cha70b]. **Cost** [Ano72g, Gue71b, RR76, Sch71b, ST73, TC75b, Ben76]. **Costs** [CH74, HS73, PS70]. **Countable** [Cra74]. **Counting** [CM71]. **Counts** [K.71d]. **Course** [Boa79a, Cro78, Geo72, Har70, Nas78, Sch74b, Str75]. **Covariance** [GC74, Ron77, Sne71, vN79]. **Covariances** [Cha70b]. **Covariate** [Har74]. **Covariates** [Kus79]. **Covariation** [J.76d, J.76e]. **Cox** [Ing75, J.79o, Cor75]. **Criteria** [Hoc72, J.78h, MPB70, Tho73]. **Criterion** [All71, Ano72e, Ano73h, Box70b, BD71, Bro79, Hel74, McL74a, ML75, NW79, SD77]. **Critical** [Zah75b]. **Cross** [Dra79, GHW79, J.79m, Mie74, Sim79, Wol78]. **Cross-Classified** [Dra79]. **Cross-Over** [Mie74]. **Cross-Tabulated** [Sim79]. **Cross-Validation** [GHW79]. **Cross-Validatory** [Wol78]. **Crossed** [HG73]. **Cryogenic** [Joi77]. **CSP** [Bla77]. **CSP-1** [Bla77]. **Cubic** [LW71]. **Cum** [Qua74b, Qua74a]. **Cumulative** [Bec74, Rey75]. **Current** [Dun78a]. **Curtailed** [Coh70, HM76a, SP72, SP74, SP77]. **Curve** [LS71b, Sne72b, SLM74]. **Curves** [SLK79, Dav70]. **CUSUM** [BJ75, JB74, MW75a, GW71]. **Cut** [BJ70b]. **Cutsem** [J.78m]. **Cyclic** [Ano74e]. **Cyrus** [Sid75].

D [Bon77, Bow77, Cas76, Dud79, Ens77, Fin75, Gib74, Gor76, Gou73, GH75, Hal77b, Har72, HK77, Ing75, J.75g, J.76h, J.77j, J.77k, J.78l, J.78k, J.78e, J.78d, J.78b, J.78o, J.79e, J.79o, J.79m, Joh73c, K.74c, Kal75, Law75b, Str75, Sys76, Wil70]. **Daniel** [Sne72a, Wei71, Lyn78]. **Data** [All74, Ano71a, BH70, Bli72, BHME73, BM76, Cha79, CR79, CG76, Dav77, Dyk71, Ell76, EB79, Ens76, Fed74b, Har75, HJ76, Hoo79, J.78f, J.78d, Jac80, JK71, KN74, KB75, Mal74, Man71a, MG74, Mar74, MN77, Mul70, Nea70, NH72, Nel72b, Nel73, NH73, O'F73, PW77, Pat76a, PS77, RTDM79, SH79, See73, Sne72b, Sne73, Ten72, WB74, Weg76, Wol74, Woo73, Zel72, BT74, Boa73, Dra79, Fed77,

Gen77, J.77m, J.79i, J.79c, Sim79, Sne72a, Wat73, Gen77, Lac71a]. **David** [Cra74, Doo72, For71, Kin79a, Mil72a, Ser73, Sim73, Weg76, Ano74e, Geo72, Gru71a, J.78c]. **Davis** [Ano80a]. **Dealing** [GS71, Gut73b]. **deCani** [Joh75]. **Decays** [SCSB76]. **Decision** [J.78h, Kin78, Kup71, Lac71b, Sym71, Win71, Hol73]. **Decisions** [J.78b, Ran70b]. **Decomposition** [Bod70, Fre74b, SCSB76]. **Defective** [BR73, SP74]. **DeFrancesco** [Sto76]. **DeGroot** [How77]. **Delay** [CP75]. **Deliveries** [BS72]. **Delphi** [J.76i]. **Densities** [BMP77, Par70]. **Density** [Gro71b, Spe71, Weg72, WRLI75]. **Departure** [Gre71]. **Depend** [Wio70]. **Dependent** [AvdL70, Bri74, Kus79, Moe74]. **Deposits** [CBI79]. **Depreciation** [CH74]. **Derivation** [Lad77]. **Derivative** [RJ78]. **Derivative-Free** [RJ78]. **Derivatives** [JB76, Wig76]. **Deriving** [Jon76a]. **Derman** [Sid75]. **Derrick** [K.74d]. **Design** [Add72, Ant77, Box70b, Box71, Buc73, Car74, Chi75, Con70, Cru78b, Dun78a, FM71, Gri73, HH74, Hil78, HS71, J.75a, J.76b, Joh78, Joi77, Luc76, Man72, Mar75, Mar76, MHC77, MH78, Mie74, OL77, PB77, SN77, See73, Ste75, Wat70a, Zac70, ZNL79, Joh73a, Kev75]. **Designing** [Joh71a, JC76, Tak72]. **Designs** [AT79, Ano72e, Ano73h, Ano73f, Ano76e, Ber72a, BD71, BD74, BH77, Cor75, DS77a, Ede74, Eva79, GK77b, GG70b, HP78, HW75, Har79, HM72, Hok74, IR77, Joh79, Jon76a, Kle75, Luc74, Luc76, Luc78, Mit74a, Mit74b, MB78a, MB78b, MA78, OM72, Par78a, Roq76, See70, SM74, Sne75b, SM76, SC71, SD75, Ste72a, Tho73, TA75, Web71, GK77a, Ano74e, Cam77, Sne76]. **detect** [GDF78]. **Detecting** [CBI79, GW75, Gut73a, Shu71]. **Detection** [Ano79g, Coo77, Dav79b, Kit79, LE73, Ros75b, TM72, Kit81]. **Determination** [Ano72g, GW71, Gru73a, Gue71b, Hal77a, Jae74]. **Determines** [Nád71]. **Determining** [AB71, MW78]. **Development** [Kee75]. **Developments** [J.78i, J.78m, J.76b, J.79g, J.79f]. **Deviation** [BMH76]. **Deviations** [For72]. **Devices** [HN70]. **Diagnostic** [BG78, DM77]. **Difference** [Hah77]. **Differences** [Sal75b]. **Different** [Par70]. **Differential** [Bri73a, Cha75a, Fin75, JB76, Sac75, Str75, Wig76]. **Differentiation** [AB74]. **Diffusion** [Ser73]. **Digamma** [Lin79]. **Digital** [J.79q, Mih75, Mih77, Nel74]. **Dimension** [Cha79, vNS76, vN79]. **Dimensional** [GLV74]. **Dimensions** [DL70]. **Dimitri** [Ziz78]. **Direct** [Aro76, Goo71]. **Directional** [Wat73]. **Disciplines** [J.79v]. **Discounting** [RR76]. **Discrete** [AvdL70, Ano77h, Bai74a, DY70, Gri72, Mac76, Mih75, Mih77, PS77, Spr78, Odo77, Smi70a]. **Discretization** [Hol75]. **Discriminant** [Dun71, HH77, Krz77, Lac74b, Lac79, McC75a, McK76, McL72, McL74b, Sor73, vNS76, vN79]. **Discrimination** [AR79, BA70, DA73, DAH73, Har73a, Hil78, MPB70, Ng76]. **Discussion** [Ant77, Eas78, Ell76, FH79, Har73a, HM71, Hoo79, Law77b, LvNN73, Luc78, Mal74, Mar74, McD75, Par72, Sne75a, Wig76, Zel72]. **Disease** [Ens78]. **Disney** [Rog70b]. **Displays** [DM77, Tuk70]. **Distributed** [Bli72]. **Distribution** [AA74, Ang74, Ano72g, AJ77, Aus73, Bai72, BE73, Bai73, Bai74b, BB79,

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H [Ano74e, Bow78, CGO07, Fed74a, Hal77b, Har72, HK77, How77, J.75g, J.76d, J.76e, J.76i, J.76h, J.78c, J.78b, J.79q, J.79k, J.79v, Jac80, JTS75, K.73b, K.73a, Kal75, Kin79b, Kra76, Lac74a, Law75b, Man73, Mer72, Ran70b, Ros75a, Sne74, Sne76, Ste75, Sto76, Sym71, Web73]. **H-Function** [J.79v]. **Haan** [Ber72b]. **Haber** [Qua71]. **Haitovsky** [Fre75]. **Haley** [J.79n]. **Half** [Zah75a, Zah75b]. **Half-Normal** [Zah75a, Zah75b]. **Hamburg** [Kin78, Win71]. **Hamdan** [Ano75f]. **Hampel** [Law75b]. **Handbook** [J.78g, K.71b, J.79j]. **Handling** [Gut73a, GDF78]. **Hannan** [Cle72a]. **Harald** [K.74b]. **Harold** [Dyk76, J.77g, J.79j, Sne76, Sta70]. **Harter** [Har72, J.75g, J.76h, Ano70f]. **Hartley** [Sne74]. **Having** [AR73, BL71]. **Hays** [Lac71b]. **Hazard** [Dan70, Jon71, Nád70b, Nel72b, Sha78]. **Hazurbazar** [Ing78b]. **Health** [J.79h]. **Heavy** [Bry74]. **Heavy-Tailed** [Bry74]. **Helge** [Boa79b]. **Helmuth** [Ens76]. **Hemker** [K.73a]. **Henri** [Fre74b, Han73]. **Henrick** [Sch74b]. **Henry** [Sal75a, Woo74b]. **Henschke** [Gro77]. **Herbert** [Gru71a, Sim73]. **Hess** [K.73a]. **Heteroscedasticity** [PB77, PDB77]. **Hickman** [Ram73]. **Hicks** [Car74]. **Higher** [Nai74]. **Higher-Way** [Nai74]. **Highway** [Ano73j, Mar73]. **Hilary** [Hun70]. **Hill** [J.78q, J.78q]. **Hilton** [Ram73]. **Hine** [Boa79a]. **Hinkley** [Ing75, J.79o]. **Hirsch** [J.79r]. **History** [Ens78, J.78k]. **Hoel** [Gil74, Jon73, Sax72, Ton72, Eri72]. **Hoerl** [Ano70f]. **Hogg** [Hei78]. **Holland** [Odo77]. **Hollander** [Gib74]. **Homogeneity** [Cho79, Sch71a]. **Honor** [J.75h, K.73d]. **Honour** [J.77l, K.74b]. **Hooper** [Fre73a]. **Hordijk** [Sys75]. **Hotelling** [JH79]. **Howard** [Hac78, Har70, Lut73]. **Huang** [For71]. **Huber** [Law75b]. **Human** [Bon77]. **Hunter** [Add79, Add79, Gra72]. **Hurst** [Dun77b]. **Hybrid** [Roq76]. **Hyperbinomial** [Gro72]. **Hyperbola** [WB74]. **Hypergeometric** [Hel71a, J.77g, J.79j]. **Hypotheses** [BH73]. **Hypothesis** [Leo70, McD75, Obe75, SLK79].

ibid [GH75]. **Identifiability** [Gri79]. **Identification** [Ray72, Kev75]. **Identified** [Nád71]. **Identifying** [Joh70c, Joh70b]. **II** [BCK78, Ens77, BJ75, BN72, BCK61, Eva71, GS71, Lac74b, NH73, TW72b, J.75g]. **III** [Cra74, Eva72, Har71, J.79q]. **Illustrated** [Mal74, Mar74, BT74]. **Implications** [BH70, Wil79a]. **Implicit** [BJ70b, BL73, Sac76]. **Implies** [Bad70, Bor72]. **Important** [JC76]. **Imprecisions** [Han75]. **Improved** [BG74, Boa79b, Box70a, HL76, SS71b, Sta79, GH75]. **Improving** [BWL78]. **Including** [J.77b]. **Incomplete** [Ano73f, HS72, OL77, Web71]. **Incorrect** [JR72]. **Increases** [LE73]. **Increasing** [And70, OB76, Sch71b]. **Increments** [AvdL70]. **Independence** [Cho73, Kra76]. **Independent** [Bai73, Lev70, McD76, SB72b, Bha73, LH77]. **Index** [Ben76, K.71a, J.77d, J.77o, Qua74b, Qua74a, J.77d, J.77f, J.77e, J.77o, J.77q, J.77p]. **Individual** [TS79, Woo73]. **Induction** [Bon76b]. **Industrial** [And70, Lyn78]. **Inefficient** [Ste72b]. **Inequalities** [HB71]. **Inequality** [Wan71]. **Inference** [Ait74, BAB72, Bis79, EB78a, FW72, Goo75, Goo76, Hil74, Hol73, Kal75, Lac71b, LL78, NS79, Pie73, Sin71, Sin73, Bon76a, Gol74, Hei78, Joh73c, K.71c, K.74c, Sta70, Sym71, Wil70, Woo74a]. **Inferences** [Bai72, TA71]. **Infinite** [Luk73]. **Influential** [Coo77]. **Information** [Ano70o, Ano71l, Ano72l, Ano73p, Ano74l, Ano75l, Ano76o, Ano77q, Ano78o, Ano78p, Ano79p, EP71, Fed74b, Hay73, Lin74, Sim76]. **Infrared** [WRLI75]. **Ingram** [Sid75]. **Inhomogeneity** [BH74]. **Initial** [Lac74b, Lac79, McL72]. **Innovation** [Dav79b, Sys78]. **Input** [MBC79]. **Insect** [HG78]. **Insensitive** [Bri73b]. **Inspection** [KO77, Lem74, Ten72, Tsi78]. **Instabilities** [MS73]. **Instantaneous** [BS72]. **Institute** [Ano71f, J.75g, J.76h, J.77k, J.78o]. **Institutions** [Jac80]. **Instrument** [Jae76, Mul70]. **Instruments** [Gru73b, Han75, Jae76, Pep73]. **Integer** [Lin75, Sha71]. **Integral** [Mil72b]. **Integrals** [J.79j]. **Integration** [Eva71, Eva72]. **Intelligence** [Hel71b]. **Interaction** [HJ76, YC78]. **Interactions** [Nai74]. **Interactive** [BH70, BH77, Mar76, J.78d]. **Interdependence** [Gor76]. **Interest** [CHH$^+$71, CH74]. **International** [Car77b, J.79k]. **Interpretation** [CO75, FB75, Sne75a, SWD70, SWD74]. **Interpreting** [Gen77]. **Interregional** [Kno71]. **Interval** [AB79, Ano77h, BE73, Cha79, Eas78, Hah77, Jae70, Jon71, Kus79, Lan72, Law78, Mac76, MF75b, O'B73, TS79]. **Intervals** [AM79, AJ77, BWL78, CM71, DV78, EB78b, FM77, Hah72, HM76b, IS76, Kam72, Kam73, Kam74, KN74, Kam77, Kap75, Law77a, MF77, Pat76a, Ros75c, SS71a, TBA70, HP73]. **Intra** [Ven70]. **Intra-Year** [Ven70]. **Introduction** [Goo75, Goo76, Hac79, Hal77b, Jer70, Ros75a, Sam73, Sym71, Zac74, Dyk76, Lan73, Bri73a, Cru78a, Dye74, Eri72, Gil74, Gro77, Hei79, Hol73, Hub78, McC72, McC78b, Mer77, Sax72, Sta70, Ton72, Woo74b, Zie78, Zys70]. **Introductory** [Man71c, Bow78, Cor71, Gra72, Joh71b, Lan75, Mil72a]. **Invariant** [KARR75, Man71b, MF73]. **Inventory** [K.74a]. **Inverse** [Ban73, BB79, Bro79, CF76, CF77, Cle72b, DS77a, DS77b, Goo70, Gow72, Hal70, Par72, PK79, Ray70, TS79, Urq73, WY78]. **Inverses** [Mar70].

Inversion [Fra77]. **Investigation** [GS71]. **Invited** [HM71]. **Involving** [And73, DW72, Har79, McK76, Riz71]. **Ionospheric** [HM73]. **Irregular** [Hok74]. **Irving** [Sym71]. **Irwin** [Bon77, Gra72]. **Isaac** [Bon76b]. **Iterative** [Cha72, HG73, Pre71]. **IV** [AT79, J.77h].

J [Add79, Ano74e, Bha72, Bis72a, Boa79a, Bon77, Bow78, Cle72a, Cro71, Dud79, Dyk76, Gil74, Gol74, Gou73, Gra72, Gri73, GH75, Ham75, Hea78, Hei76, J.75h, J75e, J.75a, J.75f, J.76b, J.76a, J.77f, J.77e, J.77l, J.77j, J.77q, J.77p, J.78p, J.78m, J.78j, J.79u, J.79m, Jer70, Jon73, K.71b, K.73b, K.73c, Kal75, Kle77, Law75b, Odo77, Ram73, Rog70d, Sax72, Sch74b, Sha71, Sid75, Sim79, Smi76, Spr72, Sta70, Ton72, Web73, Zie78]. **Jack** [Kup71]. **Jackknife** [Dun78b, GC79, Sal75a]. **Jackknife-Constructed** [Dun78b]. **Jackknifing** [Hin77b]. **Jackson** [Ano80a]. **Jagers** [K.74b]. **James** [Bel70, Qua74b, Qua74a, vdV75, DV79]. **James-Stein** [DV79]. **Jan** [Bak74, Hun74, K.71b]. **Jean** [Joh73c]. **Jenkins** [Ran70c, Kle77]. **Jerome** [And75]. **Jerzy** [Fre73b]. **Jessen** [Jon73]. **Joan** [J.79p]. **John** [Ano74e, Boa79b, Boy74, Cas76, Fre73a, Gle78, J.77b, J.77d, J.77o, Joh75, K.71e, Lac72a, Leh71, Qua74b, Qua74a, Add72, Cro71]. **Johnson** [Che71, Cru78b, Fre74a, Smi70a, Spr78, Dav70, Dun77a, Kin79b]. **Joiner** [J.78g, K.71a]. **Jonckheere** [Ode71]. **Joseph** [Con74]. **Journals** [K.71a]. **Judah** [Hog74]. **Judge** [Wil79a]. **Judgments** [Gru73a]. **Judith** [J.79k]. **Julius** [Har75, Hog74].

Kabe [K.74c]. **Kagan** [Sen75]. **Kali** [Ben76]. **Karl** [Jac80]. **Kathleen** [J.75c]. **Kay** [Ber73]. **Kececioglu** [Ziz78]. **Keeney** [J.78b]. **Kemeny** [Ham75]. **Kendall** [Fie73]. **Kenneth** [K.73c, Sch74b]. **Kernel** [BMP77]. **Kimble** [Kin79b]. **Kinetic** [PDB77]. **King** [Hay73, Kno71]. **Kleindorfer** [J.79d]. **Knowledge** [ABA72, Jac80, Rah76]. **Known** [MD71, Ste78]. **Kocherlakota** [J.75c]. **Kodell** [Smi76]. **Kolchin** [Spr79]. **Kolmogorov** [BD73, DM78, LR78, PS77]. **Kolmogorov-Smirnov** [BD73, LR78]. **Konijn** [Ste75]. **Koosis** [Boa79a]. **Kossack** [Gro77]. **Kotz** [Che71, Fre74a, Smi70a, Spr78]. **Kreyszig** [Cor71]. **Krishnaiah** [J.77h, J.78a, J.79g, J.79f]. **Kruskal** [J.79k, Lac74a]. **Krutchkoff** [MK70]. **Krzyz** [Hun74]. **Kshirsagar** [Ing78b, Kha74]. **Kumar** [Ban73, Ano71g]. **Kurtosis** [JL79, Rou73].

L
[Ber72b, Che71, Con74, Cro78, Cru78b, Dav70, Dun72, Eas72, Fed77, Fre73b, Fre74a, Gow72, Gua71, Ham75, Har72, Hol73, Hun70, J.75g, J.76b, J.76h, J.78l, J.78g, J.78b, Joh71b, K.71a, Kab74, Lac71b, Lan75, Mer79, Qua74b, Qua74a, Rog70b, Ron72, Rus73, Sal75a, Smi70a, Smi76, Spr78, Wei71, Woo74b]. **L.** [GW71]. **Laboratory** [TB75]. **Lack** [Ano72f, DH71]. **Ladany** [J.77i, J.78e]. **Lagrangian** [Gre70a]. **Lai** [K.71c]. **Lancaster** [Ros75a]. **Large** [AM79, Cha79, CR79, Gut73b, HD70, Jae76, WG79]. **Larger** [Lad77].

Largest [Aus73, RRH73]. **Larrieu** [Gua71]. **Larsen** [Boa79a]. **Larson** [Dyk76, Sta70]. **Latent** [GWM76, WGM74, WG79]. **Latin** [BCK78, BCK61, Hed71]. **Laubscher** [K.71a]. **LaValle** [Sym71]. **Law** [Sin72]. **Laws** [Sen74]. **Layout** [Dan78]. **Layouts** [Nai74]. **Leak** [PBT76]. **Leak-Testing** [PBT76]. **Leaps** [FW74]. **Least** [AF76, BD72a, FM77, GZ79, GWM76, GPS73, Har73b, HM77, J.77b, JK71, MHL77a, RJ78, See73, Wat74, HP73]. **Left** [Man75]. **Lehmann** [Mer79]. **Length** [Lem74, Rey75]. **Lengths** [RH78]. **Lennart** [K.74b]. **Lentner** [Mye74]. **Leo** [J.79c]. **Leon** [Sid75]. **Leonard** [J.75h]. **Leone** [Ano80b, Cru78b]. **Less** [Fur71]. **Lester** [Bow77]. **Letter** [And76, And77, Ano77g, BC79a, BM72, Fle71, Ham70, Haw78, HK77, JTS75, Lee79, Saw70, Smi76, SM79, Wu73, ZA75]. **Letters** [BJ70a, GMD+75, GH75, HOC+77, HJ73, JEBE74, Kru70, KBW72, LSP76, MP72, SBV79, VK76]. **Level** [Ano73f, Dic74, Luc78, MB78a, MB78b, Sac72, SS75, Web71, LH77]. **Levi** [Bon76b]. **Levy** [K.71a]. **Lewis** [Ron72, Fre73c, J.79l]. **Lieberman** [Web73]. **Life** [Bai74b, BS71, Bar72, BL71, Bli72, BK70b, Dan70, Dun74, FP77, Gru73a, IR77, J.79p, KS71, Kam77, KA71, Law71, Law73, Man72, Moe74, NL75, Nel72a, NK76, NM78, NS79, Sch74a, SLK79, Sha78, Sin71, Sin73, Smi77, Bha73]. **Life-Test** [Man72]. **Life-Testing** [Bai74b, KA71]. **Lifelength** [J.75f]. **Lifetime** [CF77]. **Lifetimes** [KKM79]. **Light** [Odo77]. **Likelihood** [AA74, AR79, Ano73k, AR73, BR73, BWL78, Coh65, CS76, DAH73, Har73a, HH73, HP71, JS76, Lem75, Mat78, MN77, MW75b, SP74, SP77, SB72a, TBA70]. **Limit** [Hah75, Sen74]. **Limits** [BS79, EB78c, EB79, Fau70, FD70, FKRO71, MN77, RSO72, TBA70, TC75a, TJ79]. **Lindman** [Sne76]. **Line** [For72, WB74]. **Linear** [ABA72, And74, Ano72g, Ano74f, Bai74b, BD72a, BL74b, Boa79b, Bro79, Coo77, Coo72, D'A71a, D'A71b, Far75, Fuc78, Gue71b, GPS73, Hal70, Har73b, Hel74, HM77, HSL76, J.75d, J.75a, J.76g, J.77b, JB76, Joh71a, Kal71, Krz77, LaM78, LS71a, Leo75, LW71, Lun75, Man71b, MF73, Mar70, MK70, MW73, McL74b, MW75b, MHL74, MHL77a, MHL77b, NW77, NW79, NH72, NH73, OM72, Pas79, Pre75, Rah76, Ron72, SG71, SS71a, Sha78, Sie75, SM74, Sor73, Spr76, SB72b, Tar76, TW72b, TMB73, Wig76, Zel72, GDF78, Kev75, For73, Hul73, Lin75, Ran70a]. **Link** [Lac74a]. **Linnik** [Sen75]. **Linstone** [J.76i]. **Living** [Ben76]. **Location** [DAH73, Har73a, J.77p, Law75b, RRH73, LR78]. **Locations** [J.77e]. **Locks** [Sie75]. **Loftsgaarden** [Hac78]. **Log** [Coh76, DA73, NS79, SS71a]. **Log-Linear** [SS71a]. **Log-Normal** [Coh76, DA73]. **Logarithmic** [WY78]. **Logistic** [AR79, BMH76, CC71]. **Lognormal** [Jon71, Lan72, NK76, Sin72]. **Lohnes** [O'F73]. **London** [Ens78]. **Loop** [BM74, BM76, Ell76, PW77]. **Loren** [Nel74]. **Lot** [BS72, Eld74]. **Lothar** [Bed74]. **Low** [Law77b, MH77]. **Lower** [GZ79, Sar71]. **Lucien** [Fre73b]. **Lukacs** [Lan73]. **Lumb** [K.73e]. **Lung** [Ens78]. **Luther** [JH73b]. **Lynwood** [Dun77a].

M [Add72, And75, Boa79a, Coo72, Dud79, Dun72, Ger75, Gib74, Hea78,

How77, Ing78b, J.76g, J.76f, J.76i, J.78h, J.79k, J.79v, J.79m, Kal75, Kha74, Lac71a, MRR78, Odo77, Ran70c, Rog70a, Sen75, Sim76, Urq73, Wil79a]. **M-Estimator** [MRR78]. **Machine** [WB75]. **Machol** [J.78e, J.77i]. **Madan** [K.71c]. **Main** [CDR79, DR77, Dic74, Nai74]. **Main-Effect** [CDR79, DR77]. **Maintain** [Dun78a]. **Maintainability** [Ziz78]. **Maintenance** [RR76]. **Majorization** [Low70]. **Making** [J.78h, Kin78, Win71]. **Malik** [Sch74b]. **Management** [Gua71, J.78p, Ziz78, Dun77b, J.78e]. **Mantel** [AK71]. **Manual** [Ziz78]. **Manufactured** [Kao72]. **Many** [Ros75b, Ros77]. **Maps** [J.79l]. **Marc** [Fre73a, J.77a]. **Marcel** [J.79b]. **Mardia** [J.79u, Wat73]. **Marginal** [Par70]. **Margolin** [Ano70f]. **Mario** [J.75d]. **Market** [Nay72]. **Markets** [Kno71]. **Markov** [Cra74, Sys75, AvdL70, Bri74, JK74, WB71, Doo72, Sys76]. **Marquardt** [SS71b]. **Marvin** [Mye74]. **Mask** [Luc73]. **Massey** [Wei71]. **Material** [BF72, Lev79]. **Mathai** [J.79v, Sim76]. **Mathematical** [Ber73, Bow77, Boy74, Cha75a, Cor71, Eri72, Fre73b, Hac79, Hal77b, Har72, Ing78a, J.75g, J.76h, J.77k, J.78o, Jon76b, Lan73, Sen75, Bis72b, Lac72a]. **Mathematics** [Cha70a, Eas72, Ham75, K.71b, Spr72, K.74b, Leh71, vdV75]. **Mathematische** [Ens77]. **Matrices** [And73, Ban73, GZ79, GC74, Urq73, Zys70, Gow72]. **Matrix** [CGO07, Fra77, Goo70, Haw75, Ray70, Ron77]. **Matter** [Ano70b, Ano70c, Ano70d, Ano70e, Ano70g, Ano70h, Ano70i, Ano70j, Ano71b, Ano71c, Ano71d, Ano71e, Ano71h, Ano71i, Ano71j, Ano71k, Ano72a, Ano72b, Ano72c, Ano72d, Ano72h, Ano72i, Ano72j, Ano72k, Ano73b, Ano73c, Ano73d, Ano73e, Ano73l, Ano73m, Ano73n, Ano73o, Ano74a, Ano74b, Ano74c, Ano74d, Ano74h, Ano74i, Ano74j, Ano74k, Ano75a, Ano75b, Ano75c, Ano75d, Ano75g, Ano75h, Ano75i, Ano75j, Ano76a, Ano76b, Ano76c, Ano76d, Ano76g, Ano76h, Ano76i, Ano76j, Ano77b, Ano77c, Ano77d, Ano77e, Ano77i, Ano77j, Ano77k, Ano77l, Ano78a, Ano78b, Ano78c, Ano78d, Ano78f, Ano78g, Ano78h, Ano78i, Ano78j, Ano79a, Ano79b, Ano79c, Ano79d, Ano79h, Ano79i, Ano79j, Ano79k]. **Matters** [Ano72e, Ano73h, BD71]. **Maurice** [Fie73, Ger75]. **Maximize** [Ano71a, Dyk71, Eva79]. **Maximum** [AA74, AR79, Ano73k, AR73, BR73, BWL78, Coh65, CS76, Gri72, HH73, HP71, JS76, Lem74, Lem75, Mat78, MN77, SP74, SP77, SB72a, SU79, TBA70]. **Maximum-Likelihood** [Ano73k]. **May** [Wio70]. **McFadden** [Bis72a]. **McNeil** [J.78d]. **Mead** [ON75]. **Mean** [All71, Bad70, Bor72, BH73, CF76, Far75, FKRO71, GW71, Jos72, Kus79, Low74, McL74a, McL74b, ML75, PK79, Vin76, Wan71, HK77, LH77]. **Meaning** [Mal74, Mar74, BT74]. **Meaningful** [WW78]. **Means** [BF74, CHH$^+$71, Fed75, Hah75, Hah77, Lan72, SU79, Ury76, WC70]. **Measure** [Igl73]. **Measurement** [BR75, Gru73b, Har75, J.79t]. **Measurements** [TB75]. **Measures** [WW78, Sne70]. **Measuring** [Gru73b, HN70, Han75]. **Median** [Wol77b]. **Medical** [Fle76, Lac72b, Ros75a]. **Meeting** [Ano70a]. **Meltzer** [Hel71b, Jac80]. **Men** [Ens78]. **Mensing** [Gle77]. **Metagames** [Lut73]. **Meters** [Joi77]. **Method**

[All74, And70, And74, Ang74, Aro76, CR79, CBI79, GHW79, Gue77, Hoo79, J.76i, Lin79, OB76, SH79, See70, TW70, Yue78, ZNL79]. **Methoden** [JH73b]. **Methodology** [Dud79, Man73]. **Methods** [Bis72b, Boa79a, BCK61, Con74, Dav77, Dav79b, Dun72, Ehr77, FM71, Goo71, Gri70, HR75, J.76d, J.76e, J.77b, J.79q, J.79b, Jae70, Lac72b, Lan72, Leo70, MBC79, Mer79, Mih75, Mih77, NH72, Pat73, Ran70a, RH78, Sal75b, San72, Sne77, Sto76, Weg72, Zel72, BCK78, And75, Cor71, For71, Gib74, J.78i, J.78f]. **Meyer** [Joh71b]. **Michael** [Car77a, Sie75]. **Micro** [Car77b]. **Micro-Organisms** [Car77b]. **Microbiological** [Car77b]. **Microscale** [Ano73j, Mar73]. **MIL** [BS79, Koy78, Koy79]. **MIL-STD** [BS79]. **MIL-STD-105D** [Koy78, Koy79]. **Milestones** [CGO07]. **Milton** [K.71e]. **Minimal** [AT79]. **Minimization** [ON75]. **Minimizing** [For72]. **Minimum** [BD74, BR73, Dic74, Far75, Hal79, Nád71, NW77, NW79, Sch74a, SA79, Sch76, SLK79, SS78, Tho73, Vin76, WK77, HK77]. **Minimum-Point** [BD74]. **MINITAB** [J.78g]. **Misclassification** [Lac74b, Lac79, McL74a, Sor71, Sor72a, Sor72b, Sor73]. **Misclassified** [Lac74b, McL72, Ten72]. **Missing** [BDH70, HG73, Joh79, Pre71, Rub76, Wat70a]. **Misuse** [Kin79b]. **Mitra** [Ban73]. **MIVQUE** [SS78]. **Mixed** [Beh72, CR79, CS76, DS79, Haw72, HH73, SWD74]. **Mixing** [BR75, Cho79, Luk73]. **Mixture** [Ano76e, Beh70, BF72, Cha79, Cor75, CO75, Cor77, CK79, GK77b, Har79, Joh70c, Joh70b, MS74, Par78b, Ray72, Sch71a, Sne73, SM74, Sne75a, Sne75b]. **Mixtures** [Cor73, Cor79, DS77a, DS77b, Gri70, LC70, SN77, SM76, GK77a]. **Model** [Ano72g, Ano73j, Ant77, BDH70, Bri74, CF77, CS76, Cor77, DS77b, GLV74, Gue71b, HBA71, Hah72, HH73, HP71, Hil78, HJF78, HM73, Leo75, Man71a, Mar73, MW78, MHC77, MPB70, MA78, Nai74, OM72, Par78b, Pas79, Rah76, RR76, SWD70, SB72b, Tar76, TA75, TC73, WK71, WB74, WG78, Wio70, GDF78, J.75d]. **Model-Discrimination** [MPB70]. **Modeling** [LS71b, LSM72, PW77, Sch75]. **Modelling** [MPBD79, J.79m]. **Models** [Ano76e, BK70a, BG78, BL73, Cle71, DS77a, DAH73, Dun74, Fuc78, GK77b, Goo71, Gri79, GPS73, Har73a, Har73b, Hel74, HM77, K.71d, Lac74b, LR76, Lun75, MS74, MW73, Mer72, Par78a, Par78b, Pre75, PDB77, San72, San73, See73, SM74, Sne75b, Sne77, Spr76, Spr78, SWD74, TW72a, Wol78, Boa73, Boa79b, Hul73, J.75a, J.76g, Ron72, Smi77]. **Moderate** [Gut73b, MF77]. **Moderate-Size** [MF77]. **Modern** [Dun77b, Spr78]. **Modes** [Beh70]. **Modification** [Dav79a, Mie74, SOE75]. **Modifications** [Zah75b]. **Modified** [DM78, KM79, Koy78, Lin79, Luc73]. **Modular** [Bod70]. **Modulus** [SU79]. **Molenaar** [Hel71a]. **Moments** [Cha70b, Gro71b, Jae74]. **Monotone** [Sen74]. **Monotonicity** [Gro71b]. **Monte** [Rel70]. **Montgomery** [Dun77a]. **Moore** [Hub78]. **Morris** [Kin78, Ran70b, Win71]. **Morrison** [J.78e]. **Mortality** [MS73]. **Most** [Ala71, Bli72, EB77b]. **Mosteller** [Lac74a, Qua75, Odo77]. **MOSUMS** [BH78]. **Motion** [CF76, Nád73, PK76, Ser73, SS74]. **Motions** [HM73]. **Moving** [CK75, RH78, Ste72b, SWD74, Wic72]. **MR** [Kit81].

MTBF [BS79]. **Mullen** [Sch74b]. **Multi** [Coh75, HP71, Sac72]. **Multi-Censored** [Coh75]. **Multi-Level** [Sac72]. **Multi-Risk** [HP71]. **Multicollinearity** [WW78]. **Multicomponent** [SCSB76]. **Multidimensional** [CR79, Goo71]. **Multifunctional** [Sac76]. **Multinomial** [AA74, Ang74, BK70b, OL77, Ten72]. **Multinormal** [HS72]. **Multiple** [Ait74, And74, Bea70, FH79, Goo71, Gor76, HG73, Haw72, LSYF79, SP74, SU79, Ury76, VM79, WB71, Cle72a, J.77g, J.78h]. **Multiplicative** [SOE75, YC78]. **Multiresponse** [BDH70, BHME73, Gri73, MPBD79]. **Multivariate** [BMP77, Cha79, Dun72, Fre74a, Gaf78, GG70a, Gut73a, HB71, J.78f, J.79i, McK79, Mil72b, Odo77, Pat73, Reg76, Ron77, Ger75, J.75c, J.76d, J.76e, J.77h, K.74c, Kha74, O'F73]. **Murdoch** [J.78p]. **Muse** [Ano79e]. **Mutually** [BCK61, Hed71, BCK78]. **Myers** [Rus73, Fed74a, Man73]. **Myint** [Cha75a]. **Myint-U** [Cha75a].

N [Bis72b, Che71, Dav70, Geo72, Gri73, J.75a, J.77n, J.77j, J.79t, J.79h, K.71a, Sim76, Smi70a]. **Nadler** [Buc73]. **Namboodiri** [J.79t]. **Narayan** [Hei79]. **Narula** [Ano80b]. **Nash** [J.77b]. **Naslund** [Dun77b]. **Natural** [Ens78]. **Naylor** [Mer72]. **Near** [AT79]. **Nearly** [Har74]. **Negative** [BG74, Bin74a, Gru71c, Gue72, MC72, Nel75, Pie73, Ron77, GH75]. **Nelder** [K.71e, ON75]. **Nerlove** [Fre73a]. **Nested** [Ede74, GG70b, OL77, TA75]. **Net** [Bin74b]. **Network** [Gor76, Mar75]. **Neutral** [Sta79]. **Neuts** [J.79b]. **Newton** [JS76]. **Neyman** [Fre73b]. **Nigel** [Lut73]. **No** [Bor72, Har73a, LvNN73, Mal74, Mar74, Par72, Zel72, GH75, HK77, Kit81, Smi76]. **Noether** [McC72, Mer77]. **Noise** [Shu71]. **Nomogram** [GW71]. **Non** [BC71, BH77, GPS73, HG73, J.77b, Joi77, Krz77, Lac74b, Man71a, Pep73, RSO72, Ron77, Tak72, TA71, Weg74, WB75]. **Non-Additive** [Man71a]. **Non-Interactive** [BH77]. **Non-Iterative** [HG73]. **Non-Linear** [GPS73, J.77b]. **Non-Negative** [Ron77]. **Non-Normal** [Tak72]. **Non-Normality** [RSO72, TA71, WB75]. **Non-Optimal** [Krz77]. **Non-Orthogonal** [BC71]. **Non-Random** [Lac74b, Pep73]. **Non-Standard** [Joi77]. **Noncentral** [MCL76, KP79]. **Noncentral-F** [MCL76]. **Nonlinear** [BD72a, BL74b, BDH70, Box70b, BL73, DV78, Dun78b, LS71a, LSM72, LvNN73, Mar70, NV73a, NV73b, RJ78, Sac76, Sha71, SS71b, Cha75b]. **Nonlinearity** [LaB77]. **Nonorthogonal** [HK70a, HK70b]. **Nonparametric** [Ano80c, BR79, Bha72, Cho73, McD79, Mer77, Weg72, Dun72, Gib74, Joh73c, K.71c]. **Nonparametrics** [Qua75, Mer79]. **Nonrandomized** [MDM77]. **Nonstationary** [HM73]. **Norbert** [Kab74, Rus73]. **Normal** [Aus73, Beh70, BR73, CC71, Cha79, Coh76, Dow73, DA73, FD70, FM77, GG70a, GW71, Gri70, GS71, Joh70c, LNN61, MD71, McM71, Mil72b, MM73, Nád71, NK76, NS79, OlHS77, RSO72, Ray72, Reg76, Riz71, Sor73, Tak72, WK77, Zah75a, Zah75b, LH77]. **Normality** [Ano75e, Fil75, Kow70, RSO72, TK72, TA71, WB75]. **Normalizing** [WY78]. **Norman** [And70, Cru78b, Fre74a, Spr78]. **Note** [AM79, Ano73i, AK71, Bai74a, Bea70, Bis78, Con70, Cro71, DR77, DL70,

DY70, Eva71, Fau70, Fra77, Hal77a, Haw72, HK75, JK71, Kap72, Ken71, Lac79, MH72, MW75a, Ng76, Sch70, SS71a, Sne71, Tho75, Ton74, Ton75, JTS75].
Notes [Coo72]. **Nuclear** [BKRS78, HS71, J.78j]. **Nuisance** [EB77b]. **Null** [LF79]. **Number** [Dic74, Gru73a, Gue71a, Wio70, Wol78]. **Numbers** [Ben76]. **Numerical** [AB74, CR79, Dil71, Dun78a, Eva71, Eva72, Lin74, RH78].

O [Hac78, HH73, Ron72, Ros75a, Sie75, Sne74]. **Objectives** [J.78b]. **Objects** [Ens76]. **Observable** [Nád70a]. **Observation** [Coo77, Joh70c, Joh70b, KS71, Lik74]. **Observations** [Ano73g, FM77, GB72, Joh70c, Joh70b, Man70a, Ray72, Sin71, TS79, BN72, HP73, Fre75, J.78f]. **Observed** [FB75, Har74]. **Obstructive** [Ens78]. **Obtain** [Gre70a]. **Obtained** [Sin71]. **Obtaining** [CK79, Gue77, Jae70, MF73]. **OC** [Kow71]. **O'Carroll** [J.79m]. **Occurrence** [Gre70b, Sap73]. **Odeh** [J.76g, J.78l, J.77k, J.78o]. **Odell** [Gow72, Ron72]. **Odoroff** [Ano77a, Ano79f]. **Olkin** [Dud79, Sid75]. **O'Muircheartaigh** [J.77m]. **One** [Bai73, FM77, GLV74, GPU76, HP73, Hoc72, JD78, KB75, Kus79, Lad77, MD71, McM71, MM73, Rah76, SS75, SD77, Wes71, Boa79a]. **One-Four** [Boa79a]. **One-Sided** [FM77, SS75, Wes71, GPU76, HP73]. **One-Way** [Kus79]. **Only** [CHH$^+$71, Nád70a]. **Operates** [DY70]. **Operating** [BM76, Ell76, PW77, SLK79]. **Operation** [And70, Wan71]. **Operational** [J.79n]. **Operations** [J.77a]. **Opinion** [Gle78]. **Optimal** [Ano77h, BN72, Bis72b, BH77, EB78a, Gor76, Gre70a, Har74, J.79d, Jon76a, Krz77, Luc78, Mac76, MW78, MCM75, Mit74a, Mit74b, MB78a, MB78b, Sim73, Sor72a, SC71, Gor76, J.77i, Ran70b]. **Optimality** [NGM70, SD75]. **Optimally** [Kam72]. **Optimization** [Bro79, HS73]. **Optimum** [BS72, CF76, HS72, Law77b, Luc74, MG74, MH77, NK76, NM78, PK79, Sch71b, GK77a]. **Orbital** [Bus71]. **Order** [Ber72a, BMH76, BD74, Gue77, Hed71, Hok74, JC76, Kal75, Kam72, Kam74, Mit74b, OM72, Qua75, SWD70, SWD74, TW72b, Weg74, Gru71a]. **Ordered** [Lik74, Man70a, Ode71]. **Ordering** [Dud79, Gar71]. **Orders** [Dic74]. **Ordinary** [MHL77a, Sac75]. **Organisms** [Car77b]. **Origin** [Joh70c, Joh70b, Ste78]. **Orkin** [Car77a]. **Orthogonal** [BC71, BCK61, CDR79, DR77, Hed71, BCK78]. **Osborne** [Lac71a]. **Ostle** [Gle77]. **Other** [J.79v]. **Otnes** [Nel74]. **Outlier** [Ano74f, JD78, Jos72, KS71, Ros77, TMB73]. **Outliers** [Ano79g, GW75, GS71, Gut73b, JD78, JMM78, Kit79, LF79, Lun75, MD71, McM71, MM73, Pre75, Ros75b, Ste72a, TM72, GDF78, Kit81]. **Outliners** [Gut73a]. **Outlying** [Ano73g, GB72]. **Output** [MBC79]. **Over-Stress** [Law77b, Man72, MH77]. **Owen** [J.77k, J.78l, J.78o, Har72, J.75g, J.76h, J.78k, Tan70].

P [Add79, And70, Dav70, Dun72, Fle76, Gow72, GH75, Hea78, Hil74, J.75b, J.77n, J.77i, J.77h, J.78e, J.78q, J.78a, J.79g, J.79d, J.79u, J.79f, Jon76b, K.71d, K.74c, Kle77, Lac72b, Law75b, O'F73, Qua71, Ram73, Ron72, Sax72,

Sim76, Sne70, Spr79, Ton72, Zac74]. **Pacemakers** [BKRS78]. **Packages** [Hub78]. **Packing** [GLV74]. **Pair** [Nád71]. **Pairwise** [Ury76]. **Paliouras** [Cas76]. **Panne** [For73]. **Paper** [Fed75, MK70]. **Papermaking** [TW72a]. **Papers** [Ano70a, Fie73, HM71, J.77l, K.73d, K.73b]. **Paradoxes** [Lut73]. **Parallel** [Bry71, Wan71]. **Parameter** [AvdL70, AJ77, BE73, Bec74, Box70a, BM76, Cha75b, Coh75, Coh76, CN77, CM71, DG71, Dun78c, Dye73, Eas76, Ell76, EB74, EB75, EB77b, EB78c, GHW79, Gru71c, Kam72, Kam73, Law77a, Lem75, Lik74, Low74, Man72, MF75a, Man75, Mat78, MC72, O'B73, Pas79, Pie73, RRH73, Rou73, TW72b, GPU76]. **Parameterizations** [Sin73]. **Parameters** [Ano73k, BD72a, BL74b, BL73, D'A71a, D'A71b, DAH73, Eng75, EB78a, Fal70, Fin76, Har73a, Has72, HH74, Jae70, Kam74, Kap75, LS71a, Man70a, Man71b, MF73, MF75b, OB76, Par78b, Pat76b, RS71, Rah76, SG71, SR75, Wio70, LR78]. **Parametric** [Rog70a]. **Parent** [YM74]. **Parking** [GLV74]. **Part** [Zel72, NH72, NH73]. **Partial** [LM72, Cha75a]. **Partially** [Har73b]. **Particles** [GLV74]. **Partitioned** [Far78]. **Partitioning** [CR79]. **Passage** [CF76, Nád73, PK76, SS74]. **Path** [Bur73]. **Patil** [K.71d]. **Patterns** [BD72b, Cor77, Dan78]. **Paul** [Ber73, Eri72, Gil74, Joh71b, Jon73, Kin79b, Odo77]. **Payne** [J.77m]. **Pearson** [Sne74, Har71]. **Penalty** [Gre70a]. **Percentage** [Ano73g, GB72, Gue77, Har71, IM70, KB75, Krz79, Ros77, Som70, YM74, TC72]. **Percentages** [RSO72]. **Percentiles** [CC71]. **Performance** [BJ75, Dub73, Jae74, JB74, KKM79, Kow70, Krz77, Luc76]. **Permuted** [J.77f, J.77q, K.71a]. **Peter** [Add72, Fre73c, J.77c, J.79l, K.73e, K.74b]. **Peto** [Ens78]. **Phase** [BC79b]. **Phenomenon** [Bry71]. **Phillip** [Fin75, Str75]. **Physical** [Cru78b, Bis72a]. **Physics** [Cha75a]. **Piersol** [Har75]. **Pieters** [Lac74a]. **Pietro** [Qua71]. **Pisani** [Kin79a]. **Pitfalls** [BK74]. **Pitman** [MC72, J.77l]. **Pitman-Type** [MC72]. **Plackett** [Fed77, Wat70a]. **Plan** [Joh70a, KO77, SP72]. **Planning** [Dan70]. **Plans** [Ano72g, BLB73, BS79, CDR79, DR77, Dic74, Gue71a, Gue71b, Hal77a, Hal79, Lad77, MCM75, MH78, PS70, Sac72, SP74, SP77, Sha79, Tak72, VM79, WB71]. **Plot** [Ano75e, Fil75, Zah75a, Zah75b]. **Plots** [LaB77, LM72]. **Plotting** [Nel72b]. **Pocket** [J.78l]. **Point** [BD74, EB74, Fre73c, MF75b, WK71, And75, J.75d]. **Points** [Ano73g, GB72, Gue77, Har71, IM70, Joh79, KB75, Krz79, Man75, Ros77, Som70, YM74, TC72]. **Poisson** [Hel71a, AT73, Coh72, CM71, CJ73, GH70, Ham72a, Jae70, Man75, Nel75, Pat73, Pat76b]. **Policies** [Sch71b, TC75b]. **Policy** [BS72, Jac80]. **Policymaking** [Jac80]. **Political** [Lut73]. **Pollution** [Ano73j, Boy74, CG76, Mar73, MS73, Sin72]. **Poly** [Kle75]. **Poly-Factor** [Kle75]. **Polynomial** [Cor75, Gaf78, LW71, Par78a]. **Polynomials** [Mal74, Mar74, BT74]. **Population** [Beh72, BSH71, FM77, HG78, Joh70c, Joh70b, McD76, RRH73, SR75, Zac70]. **Populations** [Ano73k, Dud79, Gro72, Joh70c, Joh70b, Ray72, Reg76, SS76, vN79]. **Port** [Gil74, Sax72, Ton72]. **Portable** [BK74, Whe74, Whe75]. **Positive**

[Bin74a, CF76]. **Possible** [CBI79, Fur71, MT72, Sta79]. **Postulated** [SLM74]. **Potential** [BK74, Sys75]. **Power** [BJN71, BK74, BH74, Bri73b, DW72, Dub73, FR72, For72, GC74, HK75, KARR75, LH74, Mal74, Mar74, PK76, PK79, Whe74, Whe75, Yue78, BT74]. **Powered** [BKRS78]. **Powerful** [EB77b]. **Practical** [NGM70, Bha72, Sie75]. **Practice** [Ben76, J.79m, Odo77, Pre77]. **Practices** [Eas72]. **Pranab** [Kee75]. **Pratt** [Boy74]. **Pre** [Wil79a, Rah76]. **Pre-Test** [Wil79a, Rah76]. **Precision** [Ben76, Dan70, Gru73b, Jae76]. **Prediction** [All71, All74, AM79, BSH71, Cle71, CK79, EB78b, EB79, FM77, GM79, Hah72, Hah75, Hah77, HM76b, KN74, Kam77, Law71, Law77a, Lik74, MF77, NW77, SS71a, HP73, Boa79b]. **Predictive** [Dun74]. **Predictor** [LvNN73, NV73a, NV73b, Rub76]. **Prekopa** [K.74a]. **Preliminary** [McD75, Obe75]. **Premium** [Gut73b]. **Prescribed** [Dan70]. **Presence** [GR72, JMM78, KS71]. **Present** [Jos72]. **Presented** [Ano70a]. **Preservation** [Luk73]. **Previous** [Nel72a]. **Price** [Hah79]. **Prices** [Kno71]. **Primer** [Gie74]. **Principal** [JH73a, JM79, JH79, Krz79, Wol78]. **Principles** [Car77b, Cor71, Han73]. **Pringle** [Urq73]. **Prior** [ABA72, Ano72g, Chi74, Gro72, Gue71b, PS70, Rah76]. **Probabilities** [Dun71, Sor72a, Sor72b]. **Probability** [Ano75e, Bad70, Bor72, Bur73, Fil75, Fre73b, GH70, Hac78, Hac79, Hei79, Hol75, J.77d, J.77f, J.77e, J.77l, J.77o, J.77q, J.77p, JR72, Joh71b, K.73e, Kap72, LaB77, Lac71b, Law77b, MH77, MH78, Moe72, RTDM79, Rog70d, Sam73, ST72, Sch74b, Sid75, Smi77, Sne70, Sor71, Sor73, Spe71, Spr78, Sta70, Sym71, Ton72, Weg72, Woo74b, Zac74, Bis72a, Har70, J.78k, J.79b, Mil72a, Rog70c, Zie78, Bow77, Fed74a, Gol74, Hei78, Hog74, How77, J.76f, Kup71, Lan73, Ram73, Rog70b, Wei71, Zac74]. **Probable** [Ala71]. **Probe** [JK74]. **Probit** [Gou73]. **Problem** [AT73, AF76, Gri72, HN70, Haw72, Hel74, Kal71, KA71, Law71, Lem74, MW75b, MRR78, Ray72, Ros75c, Sam78, Shu72, Wat74, LH74]. **Problems** [And75, BC71, BHME73, EB79, Gue74, HK70a, HK70b, McL74b, Riz71, Sen75, Sin72, Whi70, Boy74, J.77b, Hun74, J.79o]. **Procedure** [BR79, BKRS78, Bin74b, Bis78, Bli72, Cha72, GG70a, GR72, KKM79, MB74, O'B73, ON75, RRH73, Ros77, SR75, SS71b]. **Procedures** [Ano73a, Ano80c, Bea70, Ber78, BD78, CF76, CG76, EB77a, EB78a, FH79, Gle78, Goo71, Gut73b, Hil78, Igl73, JM79, LSYF79, LO79, Man70b, McD79, McK76, PW72, Pre71, Reg76, SS76, Ury76, Eas72, Har75]. **Process** [Ano77h, BR79, Coh72, CM71, DS79, Dun78a, EB78b, Fin76, Har79, HD70, LL78, Mac76, TW72a]. **Processes** [AvdL70, AT73, BGH73, Fre73c, Rog70b, Gil74, Sys78]. **Processing** [Gle78]. **Product** [DS79, Hah77, Kao72, OB76, YC71, Ziz78]. **Production** [Bla77, DS79, Sha79]. **Productivity** [And70]. **Products** [Hay73]. **Progamming** [AA74]. **Program** [Wat70b]. **Programmed** [Boa79a]. **Programming** [AK71, For73, Ran70a, Sie75, Sys75, Coo72, Gro77, Lin75, Sha71]. **Programs** [Hea78]. **Progress** [Ano76f, J75e]. **Progressive** [Man71b]. **Progressively** [Coh76, CN77, TW72b]. **Proper** [BJ70b]. **Properties**

[Bry74, Gro71b, Joh70a, Low76, Spr76]. **Proportion** [Wio70, Zac70]. **Proportional** [Nád70b]. **Proportionality** [Man75]. **Proportions** [AB71, BR75, BM78, Cho79, MDM77, Con74]. **Proschan** [J.75f, Smi77]. **Protection** [Gut73b]. **PrY** [Ury72]. **Psychological** [Ger75]. **Publications** [Ano75k, Ano76k, Ano76l, Ano76m, Ano76n, Ano77m, Ano77n, Ano77o, Ano77p, Ano78k, Ano78l, Ano78m, Ano78n, Ano79l, Ano79m, Ano79n, Ano79o]. **Pure** [Kee75]. **Puri** [Dun72, K.71c]. **Purpose** [ST73]. **Purves** [Kin79a].

Quadratic [Ano76e, AK71, GK77b, Lac79, Luc76, Roq76, Sne75b, SS78, TC73, Yue78]. **Quadruple** [Pat76b]. **Qualitative** [J.79c]. **Qualitative/Categorical** [J.79c]. **Qualité** [Gua71]. **Quality** [BH78, DS79, Gua71, Pat73, ST73, Tsi78, Ziz78, Kab74, Woo75]. **Quantile** [MF77]. **Quantiles** [Dye73, Has72, Kam73, SA79]. **Quantitative** [Gri73, Sto76]. **Quartic** [Mat78]. **Quasilinearized** [KME71]. **Quasimidranges** [LC70]. **Query** [Bad70, Bor72, Leo70, Wat70a].

R [And70, Bow78, Bri73a, Fed74a, Fed77, GW71, Gor76, Gri73, Hog74, Hul73, Ing75, J.75b, J.75f, J.76g, J.76d, J.76e, J.77j, J.77k, J.77h, J.78l, J.78e, J.78f, J.78d, J.78m, J.78j, J.78b, J.78a, J.78o, J.79g, J.79r, J.79o, J.79v, J.79d, J.79f, J.79m, K.73b, K.74c, Kal75, Kin79b, Kup71, Lac71b, Lac71a, Lac74a, Law75b, O'F73, Sal75a, Sen75, Smi76, Sne76, Urq73, Weg76]. **R.** [MK70, J.79p]. **Rade** [K.74b]. **Radhakrishna** [Ban73]. **Radium** [PBT76]. **Raiffa** [J.78b]. **Rainville** [Fin75, Str75]. **Raj** [Sen70]. **Ralph** [Rog70b]. **Ralston** [J.79q]. **Ramachandran** [Sen75]. **Random** [Bag70, BL71, BK70b, Bri73a, Cha70b, GLV74, HW75, J.78q, Kus79, Lac74b, Nád70a, Nai74, Pep73, Rog70b, TA75, WY78, LH77, Har75, K.71d, Spr79]. **Randomization** [TW70, You72b]. **Range** [Fed75, FKRO71, GKS75, Nea70, Smi76]. **Ranges** [McD76]. **Rank** [Ano84, BJN71, GZ79, IC79, Kra76, Mie74]. **Ranking** [AT73, BR79, Bis78, SR75]. **Ranks** [HM77, Mer79]. **Rao** [Ban73, Sen75]. **Raphson** [JS76]. **Rasch** [Ens77]. **Rate** [Bai74b, Dan70, FR72, HH77, LR76, LE73, McL74b, Sha78]. **Rates** [Ano80c, Bry71, Con74, McD79]. **Rathie** [Sim76]. **Ratio** [BL71, Dav79a, DAH73, Har73a, Jae70, ST72]. **Rationality** [Lut73]. **Ratios** [BK70b]. **Ratti** [Spr72]. **Ray** [Sau73]. **Raymond** [Jon73, Kno71, Man73]. **Rayner** [Urq73]. **Re** [Sin73]. **Re-Parameterizations** [Sin73]. **Reaction** [SLM74]. **Reactor** [HS71]. **Readings** [Fre73a, K.73c, Qua71]. **Real** [Boa79a]. **Reasoning** [Hac78]. **Received** [Ano75k, Ano76k, Ano76l, Ano76m, Ano76n, Ano77m, Ano77n, Ano77o, Ano77p, Ano78k, Ano78l, Ano78m, Ano78n, Ano79l, Ano79m, Ano79n, Ano79o]. **Reciprocals** [BK70b]. **Recognition** [Dol70]. **Recorders** [Nea70]. **Recursive** [LF79]. **Reduction** [Gen77, Par78b, Rel70, Ens76]. **Redundancy** [Gre70a]. **Redundant**

[TC75a]. **Reflected** [Coh73]. **Regime** [Rif71, WB74]. **Regions** [Dun78b, Luc76, Obe77, LR78]. **Regression** [Ait74, ABA72, And74, Ano74f, Ano84, BC71, Bea70, BL74b, Ber78, Bro77, Coo77, Cro78, DM77, Dun78b, Far75, Far78, For72, Fra77, Gaf78, Gor76, Gre71, GWM76, Hah72, Hal70, Haw75, Hem75, Hil78, HJF78, Hoc72, HSL76, HK70a, HK70b, HK75, HR75, Hoo79, IC79, J.75d, KME71, LH70, LM72, LS71a, LSM72, Mar70, MK70, MS73, McK79, MHL74, MHL77a, MHL77b, NW77, NW79, NH72, NH73, Obe77, Par70, Par78a, PW72, Rah76, Sac76, SH79, SS71a, Sne77, SD75, SD77, TMB73, WGM74, WG79, Wio70, YF76, Zel72, DV79, Ell78, McC78a, For71, Fre75, Hah79]. **Regressions** [BC79b, DH74, Fur71, FW74, MT72, Rub76, SS71b]. **Regular** [Ber72b, Gue72, TS79, GH75]. **Reinhardt** [Hac78]. **Rejecting** [Ste72a]. **Related** [Ano72e, Ano73h, BD71, For73, J.79u, JS76, Wol77a]. **Relating** [MS73]. **Relations** [Haw75]. **Relationship** [All74, McL74b, NH72, NH73, Zel72]. **Relationships** [CH70, JH73a]. **Relative** [LR76, NW77]. **Relevant** [YC71]. **Reliability** [Bha73, BGH73, Bod70, Bri74, BWL78, CB75, CH70, DY70, EB78c, FB75, Gro71a, Gru71b, Gru71c, HBA71, Hei76, Her70, HM76b, J.78j, MG74, Pie73, Rea71, Sar71, Smi77, TBA70, TC75a, Var70, WK71, WG78, Whi70, Ziz78, J.77n, Kab74, Eas72, J.75f, J.77j]. **Remark** [Rea71]. **Remarks** [AvdL70, Nel75, SB72a]. **REML** [CS76]. **Renewal** [BGH73, HD70]. **Renyi** [Rog70c]. **Reordering** [BS72]. **repair** [Bha73]. **Repairing** [HM72]. **Replacement** [CH74, IS76, RR76, Sch71b, TC75b]. **Replacements** [IR77]. **Replication** [Gre71]. **Report** [Ale72, Ano74g, Com70, Com71]. **Representation** [Lac71a]. **Required** [SdV73]. **Requiring** [Dic74]. **Research** [Cha70a, Gle78, J.79n, Ger75, Gle77, J.77a, Lac72b]. **Residual** [LM72, MT72]. **Residuals** [BD72b, Dan78, DL70, GW75, JM79, Nel73, Sne71, Woo73]. **Resolution** [AT79, LS71b, SC71, SLM74]. **Response** [CP75, CO75, HM72, HS73, Luc76, MB78b, MC73, ML75, Roq76, Sne72b, Sne75a, Nay72, Man73]. **Responses** [Sta79]. **Restricted** [AF76, CS76, Joh70a, SN77, Wat74]. **Restrictions** [Kal75]. **Results** [Bai73, BB79, Bis79, DM78, Dun78a, EB73, EB74, Hol75, LL78, McL72, Nel72a, Weg74, YC71]. **Review** [Add72, Add79, And70, And75, Ano71f, Ano74e, Bak74, Ban73, Bed74, Bel70, Ben76, Ber72b, Ber73, Bha72, Bis72a, Bis72b, Boa79b, Bon76a, Bon76b, Bon77, Bow77, Bow78, Boy74, Bri73a, Buc73, Cam77, Car77a, Car77b, Car74, Cas76, Cha75a, Cha75b, Che71, Cle72a, Con74, Coo72, Cor71, Cor73, Cra74, Cro78, Cru78a, Cru78b, Dal77, Dav70, Dav77, Dil71, Doo72, Dra79, Dud79, Dun72, Dun77a, Dun77b, Dye74, Dyk76, Eas72, Ehr77, Ens76, Ens77, Ens78, Eri72, Fed74a, Fed77, Fie73, Fin75, Fle76, For71, For73, FW72, Fre73a, Fre73b, Fre73c, Fre74b, Fre74a, Fre75, Gen77, Geo72, Ger75, Gib74, Gie74, Gil74, Gle78, Gle77, Gol74, Goo75, Goo76, Gor76, Gou73, Gow72, Gra72, Gri73, Gro77, Gru71a, Gua71, Hac78, Hac79, Hah79, Hal77b]. **Review** [Ham75, Han73, Har77, Har70, Har75, Har72, Hay73, Hea78, Hei76, Hei78,

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Study [BJN71, Dun78b, Ens78, FP77, Kee75, Lev70, Zah75a]. **Sturdy** [Qua75]. **Stuttering** [Pat76b]. **Stuttering-Poisson** [Pat76b]. **Style** [Dil71]. **Subject** [Cha72, Cha70b, HS73]. **Subrahmaniam** [J.75c, J.75c]. **Subsampling** [BF72]. **Subset** [Ber78, DH74, Gor76, Hoc72, McC75b, Pas79]. **Subsets** [Ait74, HH74, KN74, McK79]. **Substantive** [Sto76]. **Subsystem** [Bri74]. **Successes** [Gre70b, Sap73]. **Such** [Koy78]. **Sufficient** [Ing78b]. **Suitable** [WB75]. **Sujit** [Ban73]. **Sum** [BJN71, MT72, NW77, NW79, Rey75, YC71]. **Sum-of-Product** [YC71]. **Summaries** [Ano70k, Ano70l, Ano70m, Ano70n]. **Summary** [Weg72]. **Superimposed** [BGH73]. **Superiority** [Hah77]. **Surface** [HM72, HS73, Luc76, Man73, MC73, ML75]. **Surfaces** [CO75, Roq76, Sne75a]. **Survey** [J.75a, J.77m, J.78c, Law75b, Ste75, Gle78, J.79t]. **Survival** [Law77b, MH77, MH78, Hei76]. **Switching** [Koy78, Koy79]. **Symmetric** [Beh72, Luc76, SN77, K.74d]. **Symmetric-Simplex** [SN77]. **Symmetrical** [Cor77]. **Symposium** [Fre73b]. **Syntheses** [BA70]. **System** [Bod70, BWL78, DY70, EP71, GC79, Gru71b, Jae74, MG74, Sar71, ST73, Var70, Wan71, WK71, Bha73]. **Systems** [BH70, BGH73, BM74, Bri74, Bry71, Buc73, CK79, J.78j, JB76, K.73a, MC73, PW77, TC75a, Wig76, Kev75, Bak74, Mer72, Dav70, Mar75].

T [Bow78, Gow72, J.78g, J.79m, K.73d, Lan75, Rog70a, Ron72]. **Table** [GW75, JK71, TC72]. **Tables** [Ano71f, BD78, BK70b, BG78, Gar71, Goo71, Har72, J.75g, J.76h, J.77k, J.78p, J.78o, JD78, Lun75, MF73, MDM77, Sne74, SU79, J.78l, Odo78, J.78q, J.79u]. **Tabular** [Joh73b]. **Tabulated** [Sim79]. **Tailed** [Bry74]. **Tails** [RSO72]. **Tanis** [Hei78]. **Tanur** [J.79k]. **Tapiero** [J.79d]. **Tatsuoka** [Ger75]. **Taylor** [Bow77]. **Teaching** [Boa79a]. **Technique** [CK75, CM71, MW75a, Som70, Whi70]. **Techniques** [Eva71, Eva72, Fed74b, Ger75, Gua71, J.76i, J.79i, K.71c, Lin74, MC73, Rel70, SCSB76, Sne73, For73, J.78n, Mar75]. **Technology** [Dal77, J.79s]. **Technometrics** [BCK78, GH75, HK77, JTS75, Smi76, Kit81, Ton75, FW72]. **Telescoping** [HS71]. **Tell** [Bon77]. **Terms** [DS77a, DS77b, GG70a, McL74b]. **Ternary** [CK79]. **Test** [AS73, Ano75e, Bar72, BJN71, BD78, BF74, BS79, CC71, CF76, DW72, DAH73, Fil75, Fuc78, GR72, Har73a, J.77b, KP71, Lun75, Man72, MG74, MF75a, MS74, MW78, MCM75, McD75, MDM77, MH78, Mie74, Nel72a, Ng76, Obe75, Ode71, PK76, PK79, Pre75, Rah76, ST72, Sch71a, SW72, Sta79, Ste78, SI70, TK72, WDFH73, WB75, Wes71, Wil79a, Wol77a, Wol77b, BD73, LH74]. **Testimation** [Rif71]. **Testing** [Ano74f, Ant77, Bai74b, BKRS78, BC79b, Bli72, BK70b, CH73a, Dun74, FP77, GR72, Gre71, Gru73a, HJF78, Igl73, JD78, KA71, Law71, Leo70, MHC77, MS79, NL75, PBT76, Sam78, SLK79, Sha78, Smi77, TMB73, Ziz78]. **Testing-Probability** [Smi77]. **Tests** [Ano73g, BJ75, BS71, Bry74, BH73,

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